Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/692,793	LEE ET AL.
Examiner	Art Unit
Quoc A. Tran	2176

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Class	Subclass	Date	Examiner
715	512	7/6/2006	80
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventors Search (check for double patent)	7/6/2006	D
EAST (USPAT, USPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB) See Search Printout	7/6/2006	Ø
ACM Digital Library See Search Printout	7/6/2006	8